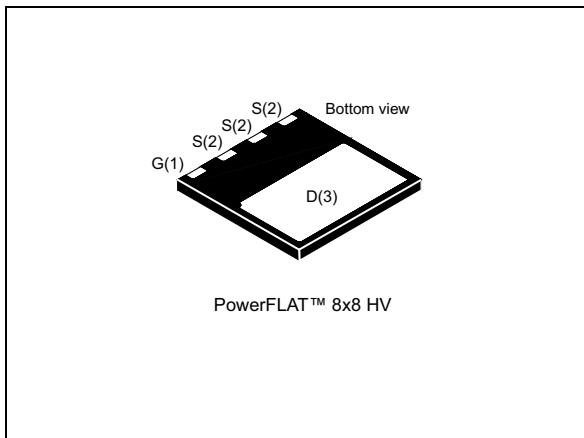
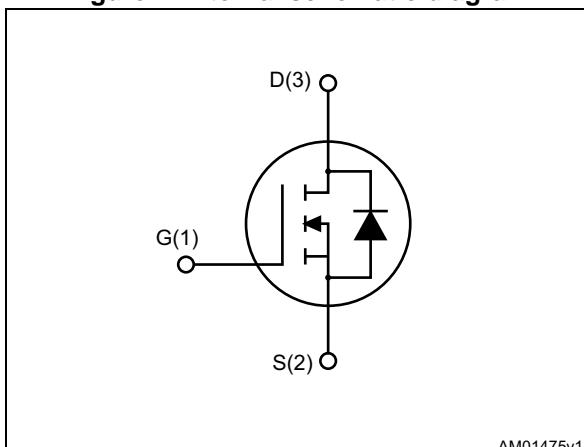


## N-channel 600 V, 0.200 $\Omega$ typ., 16 A MDmesh II Power MOSFET in a PowerFLAT™ 8x8 HV package

Datasheet – production data



**Figure 1. Internal schematic diagram**



## Features

Order code	$V_{DS} @ T_{Jmax}$	$R_{DS(on)} \text{ max}$	$I_D$
STL24NM60N	650 V	0.215 $\Omega$	16 A <sup>(1)</sup>

1. The value is rated according to  $R_{thj-case}$

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Applications

- Switching applications

## Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

Order code	Marking	Package	Packaging
STL24NM60N	24NM60N	PowerFLAT™ 8x8 HV	Tape and reel

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
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# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage	600	V
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	16	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	10	A
$I_{DM}^{(1),(3)}$	Drain current (pulsed)	64	A
$I_D^{(2)}$	Drain current (continuous) at $T_{amb} = 25^\circ\text{C}$	3.3	A
$I_D^{(2)}$	Drain current (continuous) at $T_{amb} = 100^\circ\text{C}$	1.5	A
$I_{DM}^{(2),(3)}$	Drain current (pulsed)	13.2	A
$P_{TOT}^{(2)}$	Total dissipation at $T_{amb} = 25^\circ\text{C}$	3	W
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25^\circ\text{C}$	125	W
$I_{AR}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	4	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	300	mJ
$dv/dt^{(4)}$	Peak diode recovery voltage slope	15	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	°C
$T_j$	Max. operating junction temperature	150	°C

1. The value is rated according to  $R_{thj-case}$
2. When mounted on FR-4 board of inch<sup>2</sup>, 2oz Cu
3. Pulse width limited by safe operating area
4.  $I_{SD} \leq 16\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{DS(\text{peak})} \leq V_{(BR)DSS}$ ,  $V_{DD} = 80\% V_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1	°C/W
$R_{thj-amb}^{(1)}$	Thermal resistance junction-amb max	45	°C/W

1. When mounted on FR-4 board of inch<sup>2</sup>, 2oz Cu.

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0$ , $I_D = 1 \text{ mA}$	600			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{GS} = 0$ , $V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0$ , $V_{DS} = 600 \text{ V}$ , $T_C = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0$ , $V_{GS} = \pm 25 \text{ V}$			$\pm 100$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$ , $I_D = 8 \text{ A}$		0.2	0.215	$\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{GS} = 0$ , $V_{DS} = 50 \text{ V}$ , $f = 1 \text{ MHz}$	-	1330	-	pF
$C_{oss}$	Output capacitance		-	80	-	pF
$C_{rss}$	Reverse transfer capacitance		-	3.2	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0$ , $V_{DS} = 0$ to $480 \text{ V}$	-	182	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	5	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}$ , $I_D = 16 \text{ A}$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 15</a> )	-	44	-	nC
$Q_{gs}$	Gate-source charge		-	7	-	nC
$Q_{gd}$	Gate-drain charge		-	24	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{off})}$	Turn-off delay time	$V_{DD} = 300 \text{ V}, I_D = 8 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14</a> and <a href="#">19</a> )	-	11.5	-	ns
$t_r$	Rise time		-	16.5	-	ns
$t_c$	Cross time		-	73	-	ns
$t_f$	Fall time		-	37	-	ns

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		16	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		64	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 16 \text{ A}, V_{GS} = 0$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 16 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ (see <a href="#">Figure 16</a> )	-	340		ns
$Q_{rr}$	Reverse recovery charge		-	4.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	27		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 16 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}, T_j = 150^\circ\text{C}$ (see <a href="#">Figure 16</a> )	-	404		ns
$Q_{rr}$	Reverse recovery charge		-	5.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	28		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration= 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

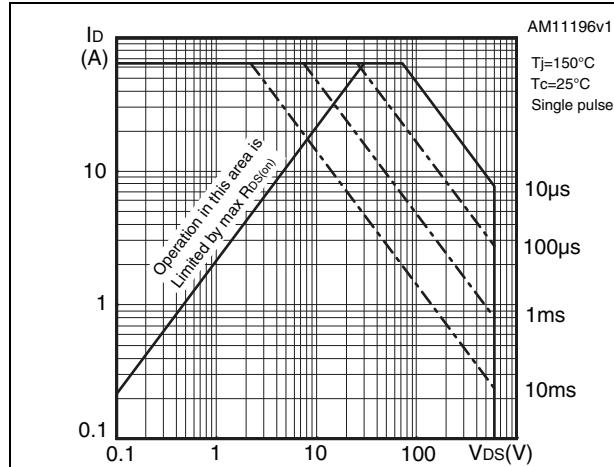


Figure 3. Thermal impedance

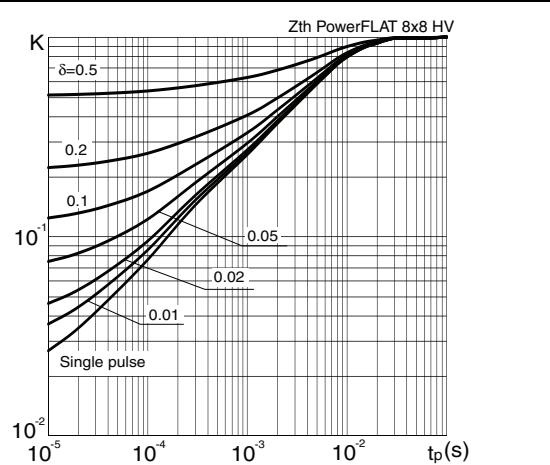


Figure 4. Output characteristics

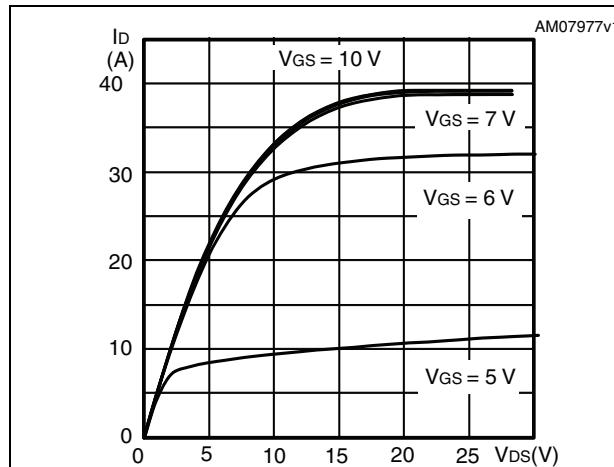


Figure 5. Transfer characteristics

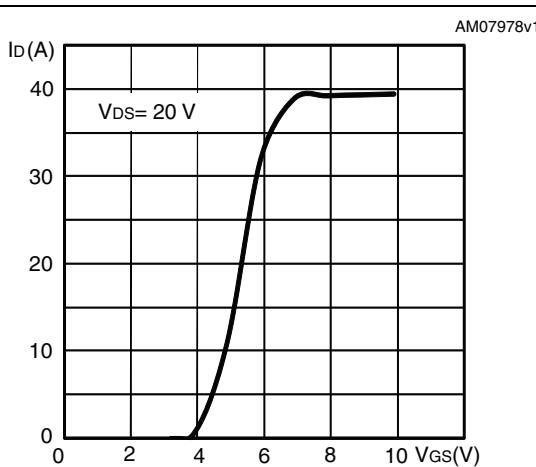


Figure 6. Gate charge vs gate-source voltage

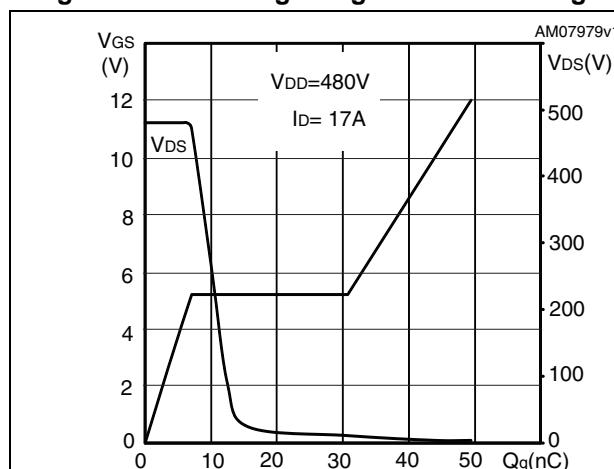
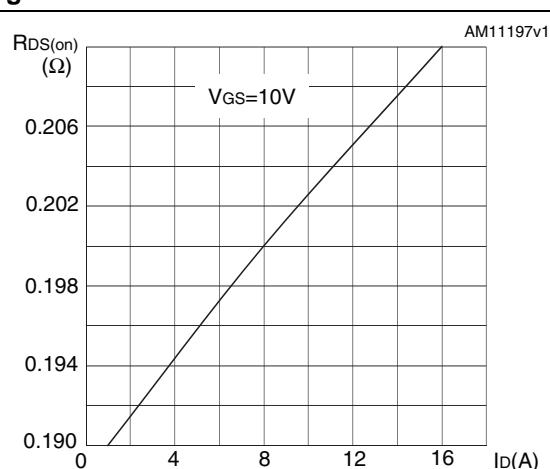
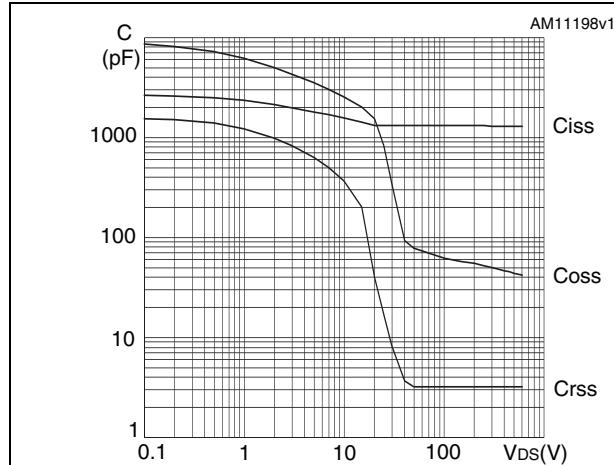
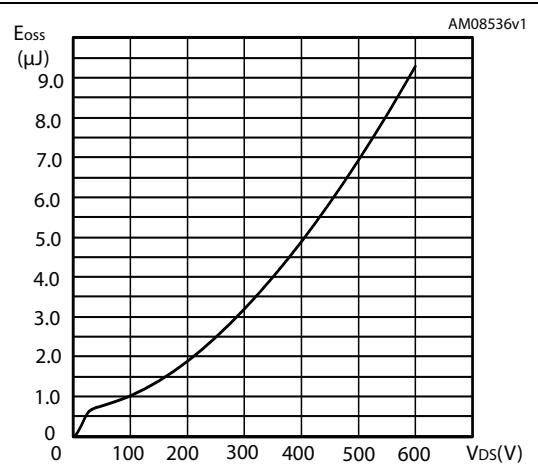
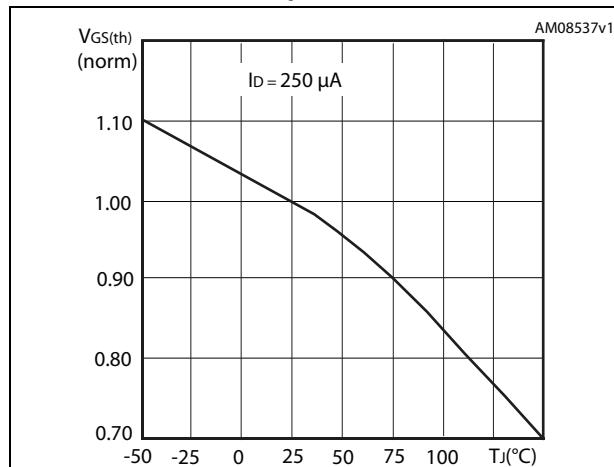
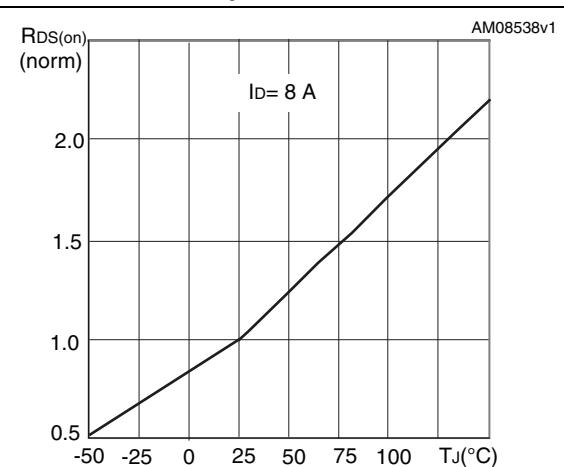
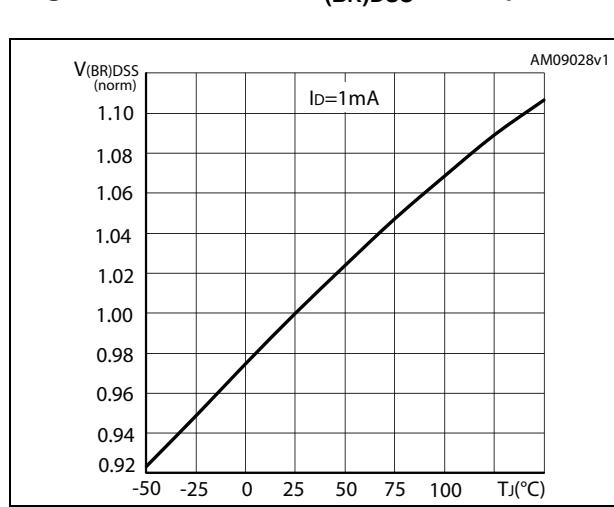
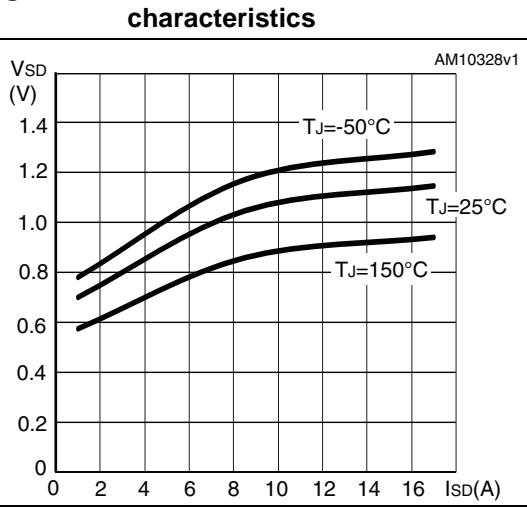


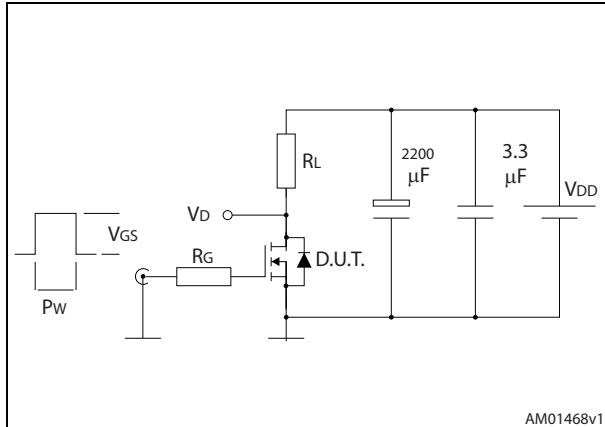
Figure 7. Static drain-source on-resistance



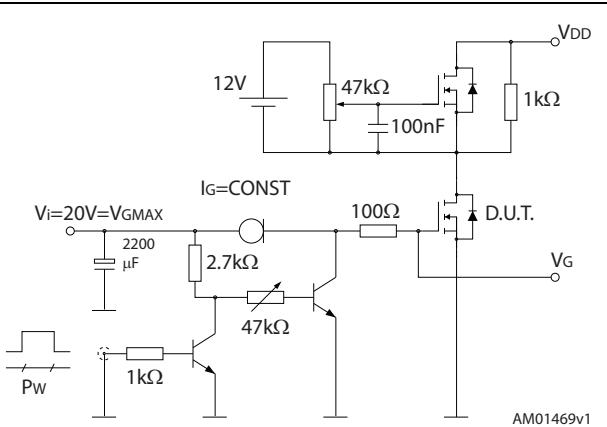
**Figure 8. Capacitance variations****Figure 9. Output capacitance stored energy****Figure 10. Normalized gate threshold voltage vs temperature****Figure 11. Normalized on-resistance vs temperature****Figure 12. Normalized  $V_{(BR)DSS}$  vs temperature****Figure 13. Source-drain diode forward characteristics**

### 3 Test circuits

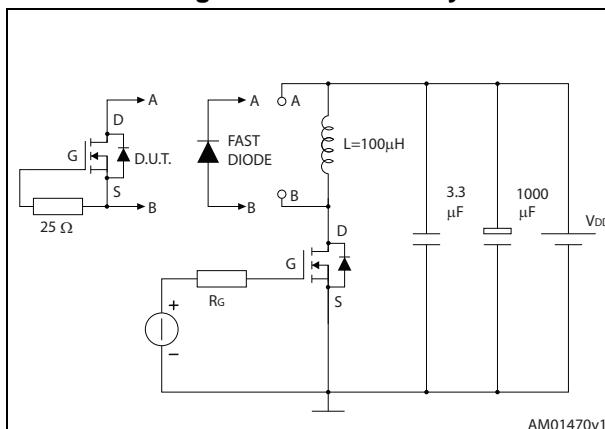
**Figure 14. Switching times test circuit for resistive load**



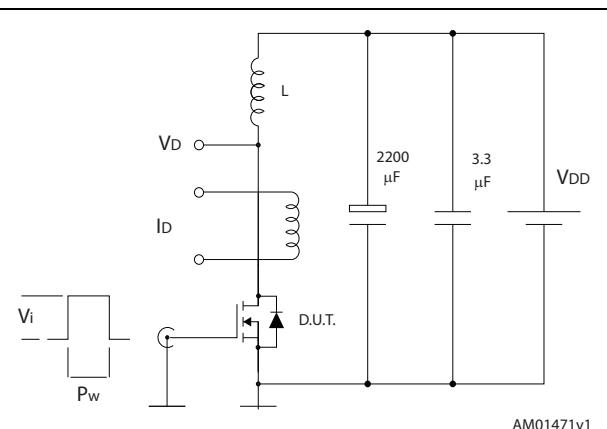
**Figure 15. Gate charge test circuit**



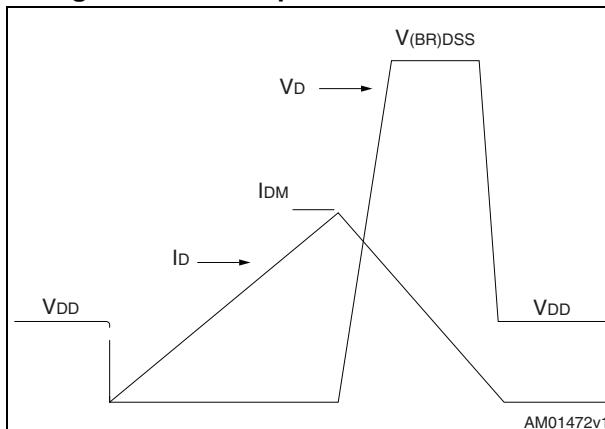
**Figure 16. Test circuit for inductive load switching and diode recovery times**



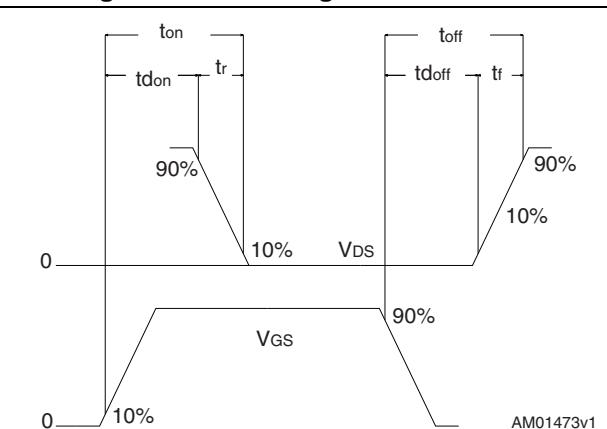
**Figure 17. Unclamped inductive load test circuit**



**Figure 18. Unclamped inductive waveform**

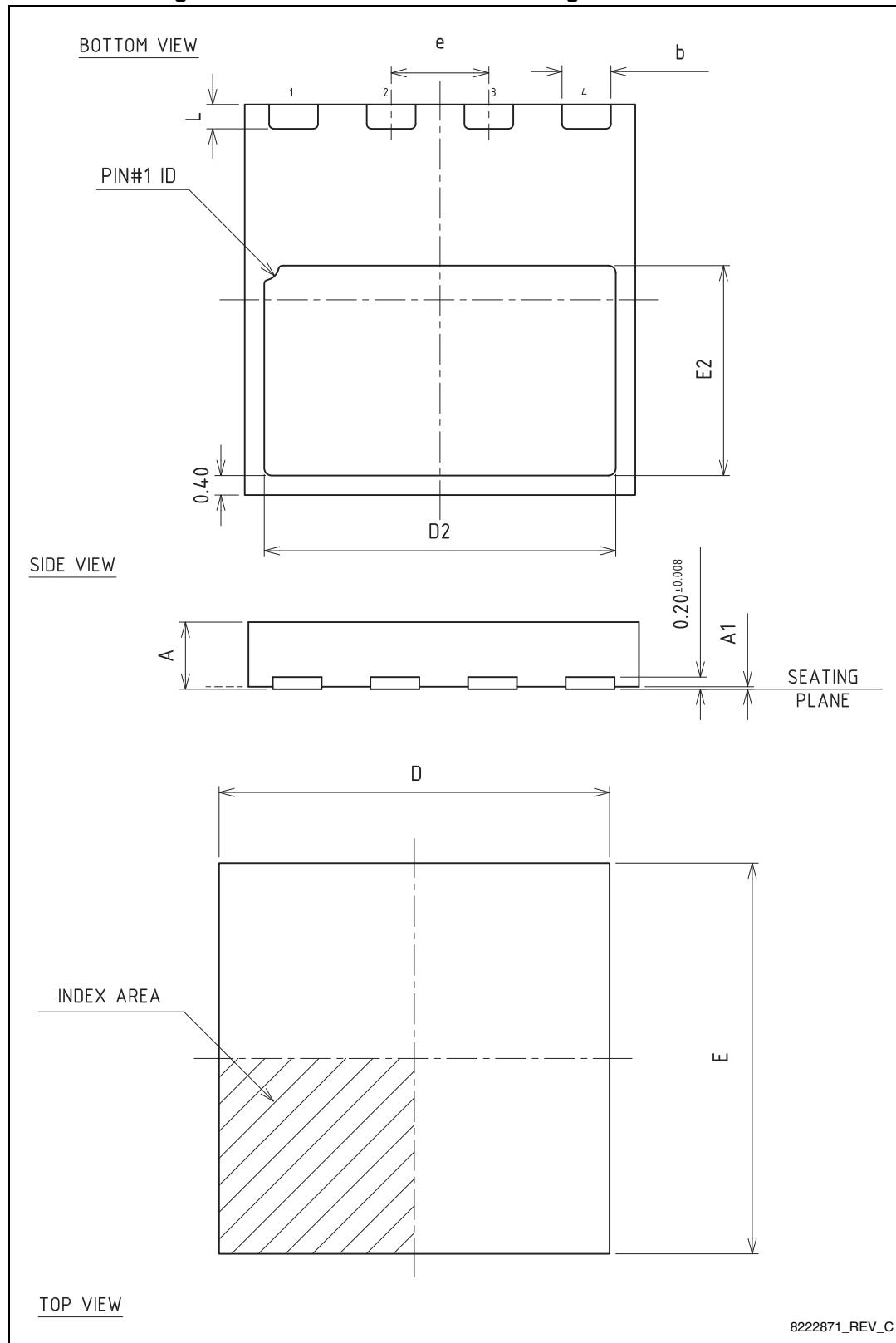


**Figure 19. Switching time waveform**



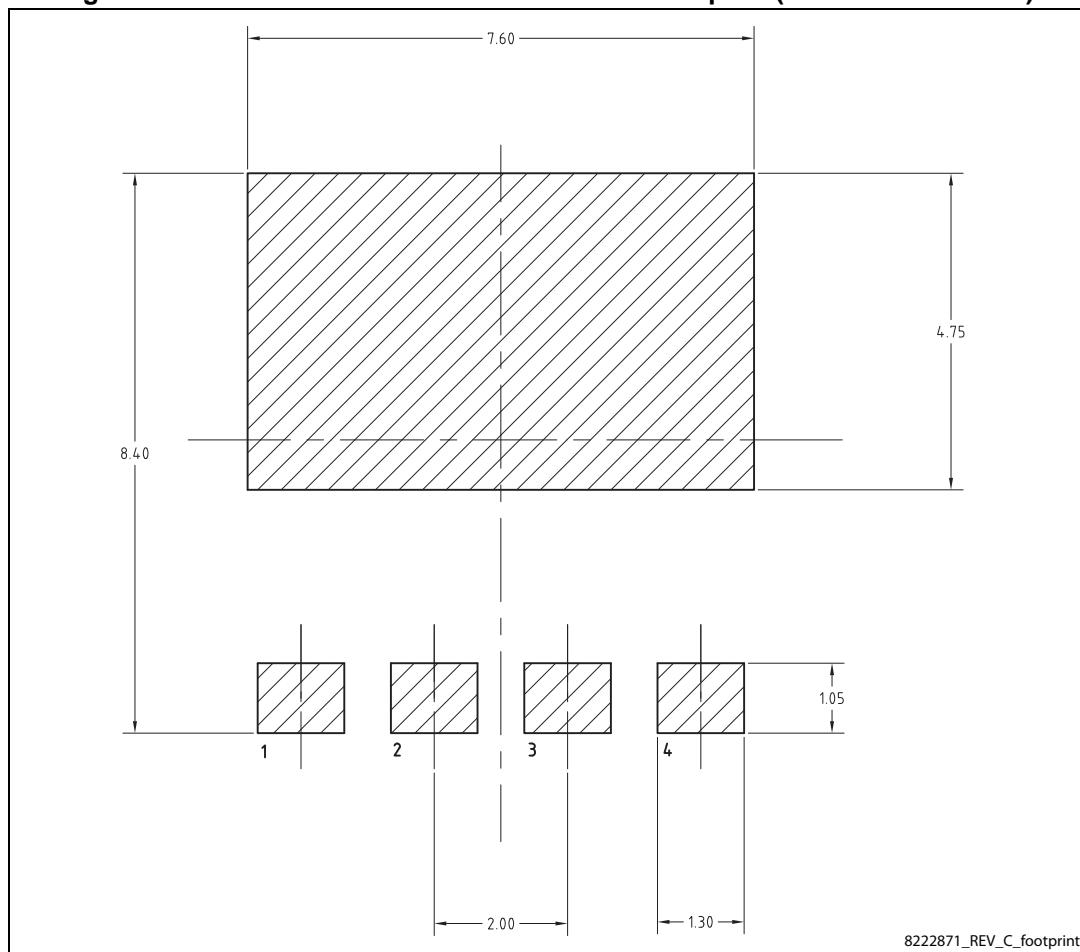
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

**Figure 20. PowerFLAT™ 8x8 HV drawing mechanical data**

**Table 8. PowerFLAT™ 8x8 HV mechanical data**

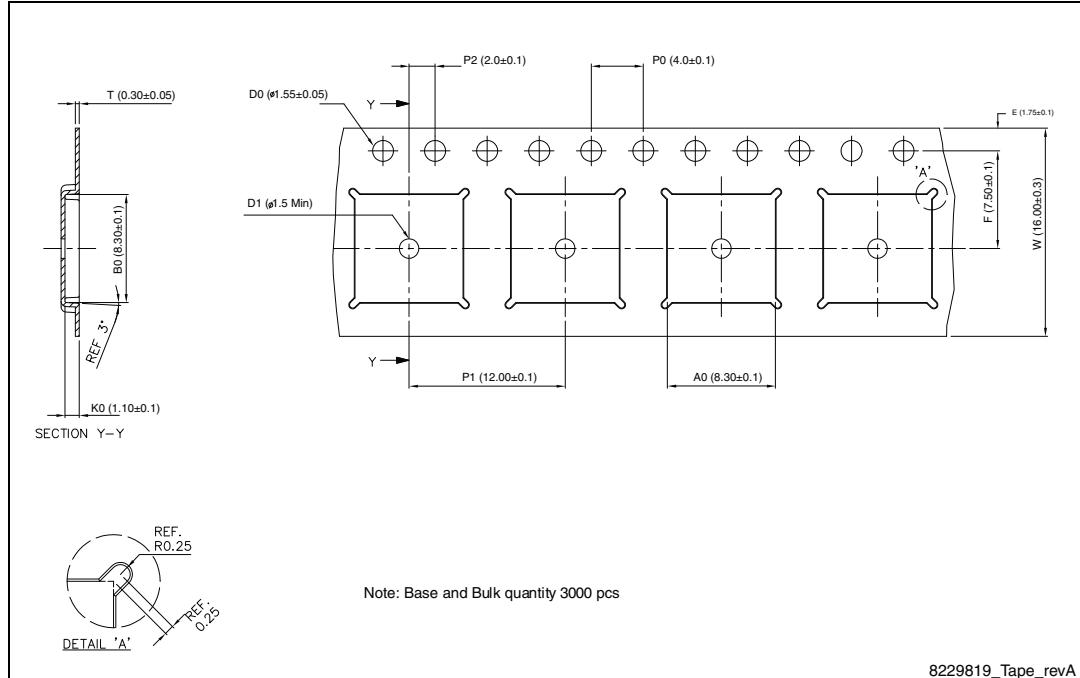
Dim.	mm		
	Min.	Typ.	Max.
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
e		2.00	
L	0.40	0.50	0.60

**Figure 21. PowerFLAT™ 8x8 HV recommended footprint (dimensions in mm.)**

8222871\_REV\_C\_footprint

## 5 Packaging mechanical data

**Figure 22. PowerFLAT™ 8x8 HV tape**



**Figure 23. PowerFLAT™ 8x8 HV package orientation in carrier tape.**

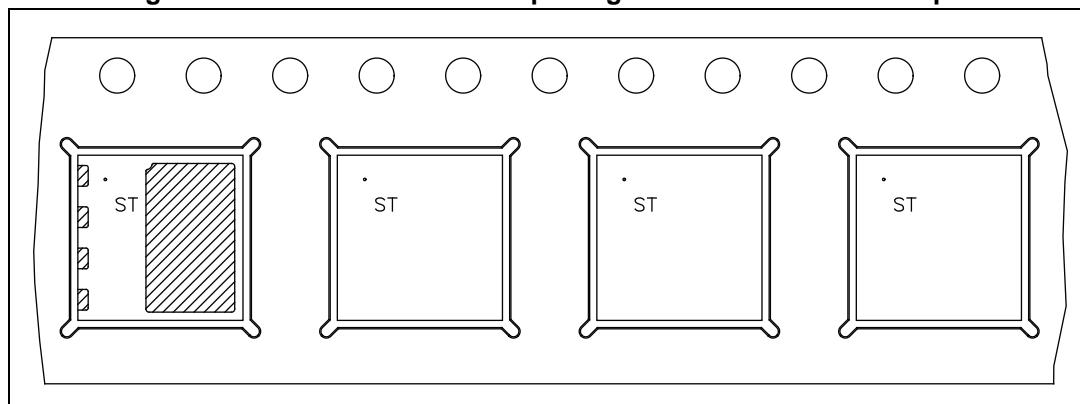
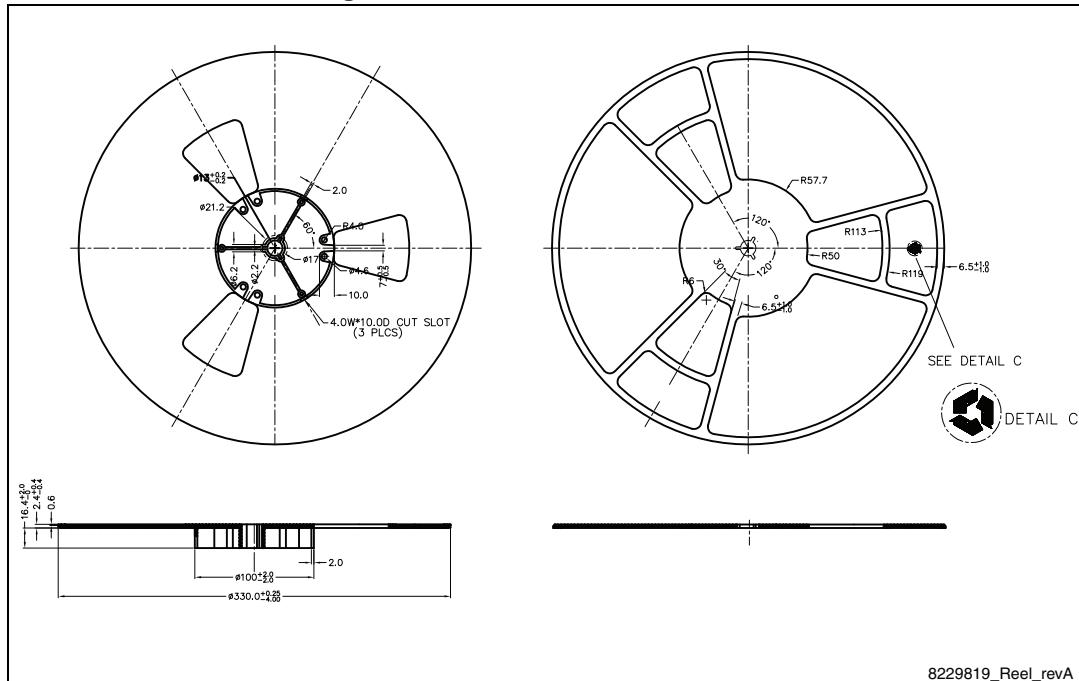


Figure 24. PowerFLAT™ 8x8 HV reel



8229819\_Reel\_revA

## 6 Revision history

Table 9. Document revision history

Date	Revision	Changes
05-Jan-2011	1	First release.
10-Nov-2011	2	<ul style="list-style-type: none"><li>– <a href="#">Section 4: Package mechanical data</a> has been updated</li><li>– Minor text changes</li></ul>
04-Jun-2013	3	<ul style="list-style-type: none"><li>– <a href="#">Section 2.1: Electrical characteristics (curves)</a> has been added</li><li>– Document status promoted from preliminary data to production data</li><li>– Minor text changes</li><li>– Added: <math>I_{DM}</math> parameter on <a href="#">Table 2</a></li></ul>
24-Jul-2014	4	<ul style="list-style-type: none"><li>– Modified: the entire typical values in <a href="#">Table 6</a></li><li>– Updated: <a href="#">Section 4: Package mechanical data</a></li><li>– Minor text changes</li></ul>

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